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NEW AGILENT TESTER FOR PARAMETRIC PRODUCTS

407x/4080x product line

The Voiron plant has huge experience in parametric test and

more especially on Keithley

products. Now with support of

Agilent, Synergie CAD PSC is able

to manufacture and test probe card

for Agilent femto Ampere range

To control the line Synergie CAD

PSC has also developed a program

testers 4073-408X.

measurements.

Synergie CAD PSC invest to cover new parametric probe card products



B1500 Tester

development of the site by investing several K€ in a new probe card test equipment based around the B1500 Agilent plateform.

"The expertise in Parametric test at the Voiron plant will be developed and will become the standard for the whole of Synergie Cad " said Alain Librati, President of Synergie CAD Group.

As is standard in Voiron, the tester and also the custom made interconnection box have been installed in the clean room to guarantee quality and repeatability of

Characterizations



order In to guaratee the production repeatbility, a full qualification of the process Then the board chain were done. First, the qualification was tester itself was checked after unpacking and the design was really calibrated for repeatable compatible with fast performance. Then the cables were also checked to ensure they were compatible for the measurements they would take.

Then after assembling the test box, a full system

qualify each part (cables, mechanical parts, pogo pins, ect...)

performed to check that femto ampere



SPECIFICATION S	VALUES
Probe Card	
Minimum Pitch	80 µm
Minimum Pad dimensions	50 µm
Number of probes	1-48
Probe position alignment accuracy	+/- 5 μm
Operating temperature	-40 °C to 200 °C
Typical Overdrive	3 mils
Туре	Coaxial Epoxy needles
Material	Copper Beryllium or Tungsten Rhenium
Tip diameter	1 to 2 mils (25 to 50 μm)
Tip length	7 to 25 mils (175 to 625 μm)
Planarity	+/- 5 μm
Material	Aluminum, Copper, Polysilicon, other
Probe mark dimensions	30 to 60 µm
Leakage : Pin to Ground , Pin to Pin 4073 / 4082	1 fA/V @ 10s 10 fA/V @ 1s
Typical parasitic capacitance	NA
Typical DC contact resistance (Probe)	0.5 to 1 Ohm
Maximum DC contact resistance (Tip to Test equipment)	2 Ohms +/- 1
Material	Polyimide

Contact List



Fig. 2

and

different results of each steps and it is notable that the PCB designed is very good, as results are improved compare to a test with the test box alone.

Then a full probe card assembly were done and tested and Fig. 2 shows the results of this probe card tested on the tester.

The Fig. 1 shows the